

June 1988 Revised September 2000

74F219

64-Bit Random Access Memory with 3-STATE Outputs

General Description

The 74F219 is a high-speed 64-bit RAM organized as a 16-word by 4-bit array. Address inputs are buffered to minimize loading and are fully decoded on-chip. The outputs are 3-STATE and are in the high-impedance state whenever the Chip Select $\overline{\rm (CS)}$ input is HIGH. The outputs are active only in the Read mode. This device is similar to the 74F189 but features non-inverting, rather than inverting, data outputs.

Features

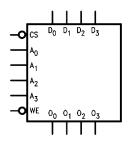
- 3-STATE outputs for data bus applications
- Buffered inputs minimize loading
- Address decoding on-chip
- Diode clamped inputs minimize ringing
- Available in SOIC (300 mil only)

Ordering Code:

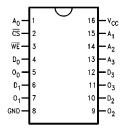
Order Number	Package Number	Package Description
74F219SC	M16B	16-Lead Small Outline Intergrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F219SJ	M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F219PC	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Unit Loading/Fan Out

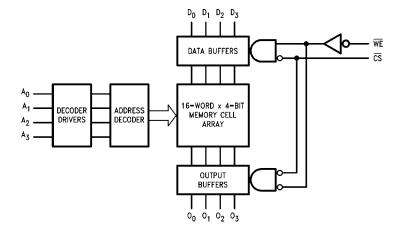
Pin Names	Decembries	U.L.	Input I _{IH} /I _{IL}		
	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
A ₀ -A ₃	Address Inputs	1.0/1.0	20 μA/-0.6 mA		
cs	Chip Select Input (Active LOW)	1.0/2.0	20 μA/–1.2 mA		
WE	Write Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA		
D ₀ –D ₃	Data Inputs	1.0/1.0	20 μA/-0.6 mA		
O ₀ -O ₃	3-STATE Data Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)		

Function Table

Inputs		Operation	Condition of Outputs			
cs	WE	Operation	Condition of Outputs			
L	L	Write	High Impedance			
L	Н	Read	True Stored Data			
Н	X	Inhibit	High Impedance			

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

Block Diagram



Absolute Maximum Ratings(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias -55°C to +150°C

V_{CC} Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC}

3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

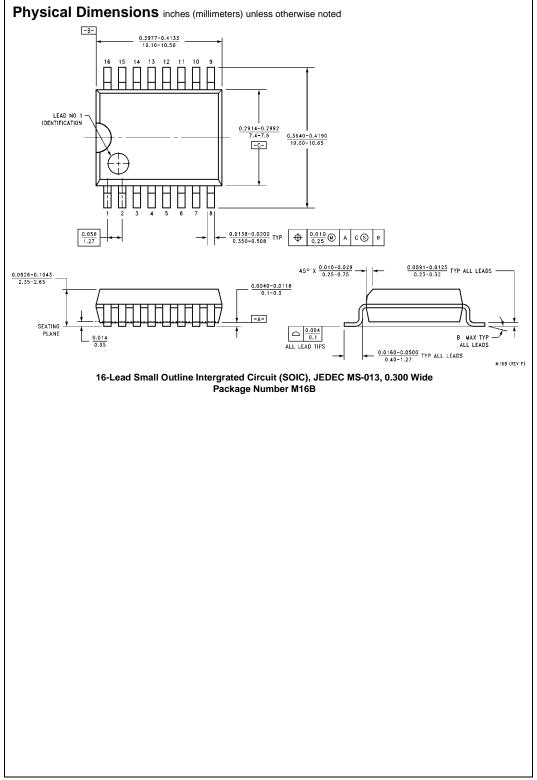
Symbol	Parameter		Min	Тур	Max	Units	V _{CC}	Conditions	
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = -18 mA	
V _{OH}	Output HIGH	10% V _{CC}	2.5					$I_{OH} = -1 \text{ mA}$	
	Voltage	10% V _{CC}	2.4			V	Min	$I_{OH} = -3 \text{ mA}$	
		$5\% V_{CC}$	2.7				IVIII1	$I_{OH} = -1 \text{ mA}$	
		$5\% V_{CC}$	2.7					$I_{OH} = -3 \text{ mA}$	
V _{OL}	Output LOW	10% V _{CC}			0.5	V	Min	I _{OL} = 24 mA	
	Voltage								
I _{IH}	Input HIGH				5.0	^	May	\/ 0.7\/	
	Current				5.0	μA Max		V _{IN} = 2.7V	
I _{BVI}	Input HIGH Current				7.0	^	Max	1/ 7.01/	
	Breakdown Test				7.0	μА	IVIAX	V _{IN} = 7.0V	
I _{CEX}	Output HIGH				50	μА	Max	V - V	
	Leakage Current				50	μΑ	IVIAX	$V_{OUT} = V_{CC}$	
V _{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$	
	Test		4.73			V	0.0	All Other Pins Grounded	
I _{OD}	Output Leakage				3.75	^	0.0	$V_{IOD} = 150 \text{ mV}$	
	Circuit Current				3.73	μА	0.0	All Other Pins Grounded	
I _{IL}	Input LOW				-0.6	mA Max		$V_{IN} = 0.5V (A_n, \overline{WE}, D_n)$	
	Current				-1.2			$V_{IN} = 0.5V (\overline{CS})$	
l _{OZH}	Output Leakage Current				50	μΑ	Max	V _{OUT} = 2.7V	
l _{OZL}	Output Leakage Current				-50	μΑ	Max	V _{OUT} = 0.5V	
los	Output Short-Circuit Current		-60		-150	mA	Max	V _{OUT} = 0V	
I _{ZZ}	Bus Drainage Test				500	μΑ	0.0V	V _{OUT} = 5.25V	
Icc	Power Supply Current			37	55	mA	Max		

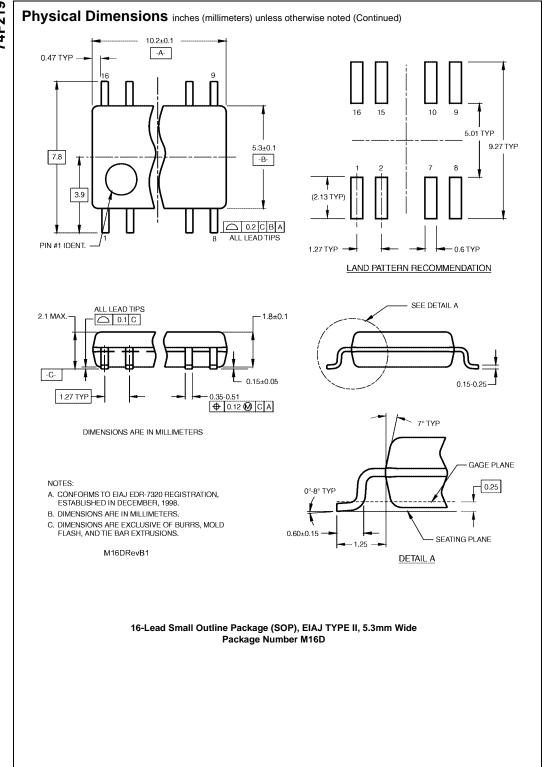
AC Electrical Characteristics

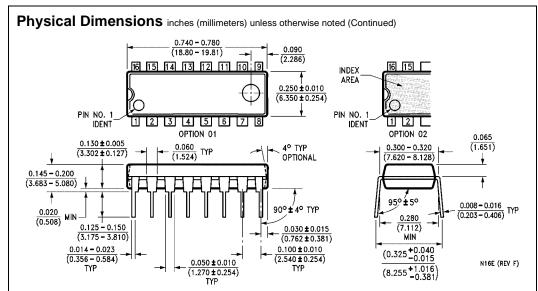
Symbol	Parameter		$T_A = +25$ °C $V_{CC} = +5.0$ V $C_L = 50$ pF		v _{cc} =	to +125°C +5.0V 50 pF	$T_A = 0$ °C $V_{CC} = C_L = 0$		Units
		Min	Тур	Max	Min	Max	Min	Max	
t _{PLH}	Access Time, HIGH or LOW	10.0	18.5	26.0	9.0	32.0	10.0	27.0	ns
t _{PHL}	A _n to O _n	8.0	13.5	19.0	8.0	23.0	8.0	20.0	115
t _{PZH}	Access Time, HIGH or LOW	3.5	6.0	8.5	3.5	10.5	3.5	9.5	
t _{PZL}	CS to O _n	5.0	9.0	13.0	5.0	15.0	5.0	14.0	ns
t _{PHZ}	Disable Time, HIGH or LOW	2.0	4.0	6.0	2.0	8.0	2.0	7.0	115
t _{PLZ}	CS to O _n	3.0	5.5	8.0	2.5	10.0	3.0	9.0	
t _{PZH}	Write Recovery Time	6.5	20.0	28.0	6.5	37.5	6.5	29.0	
t _{PZL}	HIGH or LOW, WE to O _n	6.5	11.0	15.5	6.5	17.5	6.5	16.5	ns
t _{PHZ}	Disable Time, HIGH or LOW	4.0	7.0	10.0	3.5	12.0	4.0	11.0	115
t _{PLZ}	WE to O _n	5.0	9.0	13.0	5.0	15.0	5.0	14.0	

AC Operating Requirements

		$T_A = +25$ °C $V_{CC} = +5.0V$		$T_A = -55$ °C to +125°C $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units	
Symbol	Parameter								
		Min	Max	Min	Max	Min	Max		
t _S (H)	Setup Time, HIGH or LOW	0		0		0			
t _S (L)	A _n to WE	0		0		0		ns	
t _H (H)	Hold Time, HIGH or LOW	2.0		2.0		2.0		115	
t _H (L)	A _n to WE	2.0		2.0		2.0			
t _S (H)	Setup Time, HIGH or LOW	10.0		11.0		10.0			
t _S (L)	D _n to WE	10.0		11.0		10.0		ns	
t _H (H)	Hold Time, HIGH or LOW	0		2.0		0		115	
t _H (L)	D _n to WE	0		2.0		0			
t _S (L)	Setup Time, LOW	0		0		0			
	CS to WE	0		U		U		ns	
t _H (L)	Hold Time, LOW	6.0		7.5		6.0		115	
	CS to WE	0.0		7.5		0.0			
t _W (L)	WE Pulse Width, LOW	6.0		15.0		6.0		ns	







16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N16E

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